

## IN THE CLAIMS

In this Response, Applicant has not amended the claims. The listing of the claims below is presented for the convenience of the Examiner only.

1. (Previously Presented) A method for monitoring a manufacturing process of a plurality of physical objects, the method comprising:

receiving at least one process parameter from a sensor that monitors a process parameter of a sub-production installation of the manufacturing process while the plurality of physical objects is being manufactured;

automatedly performing an analysis;

determining, based on the analysis, that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion;

marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement; and

preventing values associated with the at least one marked physical object from affecting a product quality measurement of the plurality of physical objects.

2. (Previously Presented) The method of claim 1 wherein the physical object is a wafer.

3. (Previously Presented) The method of claim 1 wherein the analysis is a statistical analysis.

4. (Previously Presented) The method of claim 1 wherein the values of the at least one process parameter are measured when the plurality of physical objects is being manufactured.

5. (Previously Presented) The method of claim 1, further comprising:  
sending the at least one marked physical object for a special measurement.

6. (Previously Presented) The method of claim 5 wherein the special measurement is a measurement for checking the quality of the at least one marked physical object.
7. (Previously Presented) The method of claim 1, further comprising:  
continuing the manufacturing process for any of the plurality of physical objects not marked as failing the prescribed selection criterion.
8. (Previously Presented) The method of claim 1, wherein the selection criterion is a quality characteristic of the manufacturing process.
9. (Previously Presented) The method of claim 1, wherein the selection criterion is not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.
10. (Previously Presented) A device for monitoring a manufacturing process of a plurality of physical objects, the device comprising:  
a processor, the processor configured to cause the device to:  
receive at least one process parameter from a sensor that monitors a process parameter of a sub-production installation of the manufacturing process while the plurality of physical objects are being manufactured;  
perform an analysis using values of the at least one process parameter;  
mark at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;  
prevent values associated with the at least one marked physical object from affecting a product quality measurement of the plurality of physical objects;  
and  
send the at least one marked physical object for special treatments.
11. (Previously Presented) A computer-readable storage medium, in which a program for monitoring a manufacturing process of a plurality of physical objects is stored, the program performing method steps comprising:

receiving at least one process parameter from a sensor that monitors a process parameter of a sub-production installation of the manufacturing process while the plurality of physical objects is being manufactured;

performing analysis using values of the at least one process parameter;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

preventing values associated with the at least one marked physical object from affecting a product quality measurement of the plurality of physical objects; and

sending the at least one marked physical object for special treatments.

12. (Previously Presented) A computer-readable medium comprising a computer program element for monitoring a manufacturing process of a plurality of physical objects, the computer program comprising:

receiving at least one process parameter from a sensor that monitors a process parameter of a sub-production installation of the manufacturing process while the plurality of physical objects is being manufactured;

performing an analysis using values of the at least one process parameter;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

preventing values associated with the at least one marked physical object from affecting a product quality measurement of the plurality of physical objects; and

sending the at least one marked physical object for special treatments.

13. (Previously Presented) A method for monitoring a manufacturing process of a plurality of physical objects, the method comprising:

performing an analysis by means of an evaluation unit using values of at least one process parameter of the manufacturing process of the plurality of physical objects, the values being measured while the plurality of physical objects is being manufactured;

determining that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion;

marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement;

removing the at least one marked physical object from the manufacturing process; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

14. (Previously Presented) A device for monitoring a manufacturing process of a plurality of physical objects with a processor which is set up in such a way to perform method steps, the method steps comprising:

performing an analysis by means of an evaluation unit using values of at least one process parameter of the manufacturing process of the plurality of physical objects, the values being measured while the plurality of physical objects is being manufactured;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

15. (Previously Presented) A computer-readable storage medium, in which a program for monitoring a manufacturing process of a plurality of physical objects is stored, the program performing method steps comprising:

performing analysis by means of an evaluation unit using values of at least one process parameter of the manufacturing process of the plurality of physical objects, the values being measured while the plurality of physical objects is being manufactured;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

16. (Previously Presented) A computer-readable medium comprising a computer program element for monitoring a manufacturing process of a plurality of physical objects, the computer program comprising:

performing an analysis by means of an evaluation unit using values of at least one process parameter of the manufacturing process of the plurality of physical objects, the values being measured while the plurality of physical objects is being manufactured;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.